

**RELIABILITY DATA  
LTC1966  
1/20/2009**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SOIC/SOT/MSOP SSOP/TSSOP	231	0201	0318	231.00	0
	77	0318	0318	77.00	0
	308			308.00	0

**• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(4)</sup> AT +85°C	NUMBER OF FAILURES
	0			0.00	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,166	0221	0450	329.38	0
	1,166			329.38	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP SSOP/TSSOP	363	0221	0746	207.89	0
	420	0243	0524	243.74	0
	783			451.63	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP SSOP/TSSOP	350	0226	0824	223.40	0
	254	0243	0524	209.90	0
	604			433.30	0

(1) Assumes Activation Energy = 0.7 Electron Volts  
(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 38.43 FITS  
(3) Mean Time Between Failures in Years = 2,968  
(4) Assumes 20X Acceleration from 85°C to +131°C  
Note: 1 FIT = 1 Failure in One Billion Hours.